

HB56G19 Series

1,048,576-Word x 9-Bit High Density Dynamic RAM Module

DESCRIPTION

The HB56G19 is a 1M x 9 dynamic RAM module, mounted two 4 Mbit DRAM (HM514400AS) sealed in SOJ package and 1 Mbit DRAM (HM511000AJP) sealed in SOJ package. An outline of the HB56G19 is 30-pin single in-line package having lead types (HB56G19A), socket type (HB56G19B/GB). Therefore, the HB56G19 makes high density mounting possible without surface mount technology. The HB56G19 provides common data inputs and outputs and also provides separate I/O on parity bit for parity check. Its module board has decoupling capacitors beneath each SOJ.

FEATURES

- 30-pin Single In-line Package
Lead Pitch 2.54mm
- Single 5V ($\pm 10\%$) Supply
- High Speed
Access Time 60 ns/70 ns/80 ns/100 ns (max)
- Low Power Dissipation
Active Mode 1705 mW/1540 mW/
1375 mW/1210 mW (max)
Standby Mode 33 mW (max)
- Fast Page Mode Capability
- 1,024 Refresh Cycle (16 ms)
- 2 Variations of Refresh
RAS Only Refresh
CAS Before RAS Refresh
- TTL Compatible

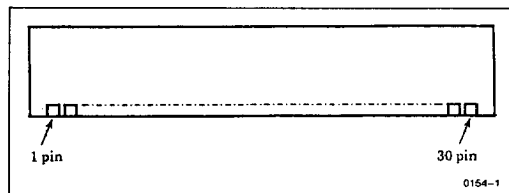
ORDERING INFORMATION

Part No.	Access Time	Package
HB56G19A-6A	60 ns	30-pin SIP Low Profile Lead Type
HB56G19A-7A	70 ns	
HB56G19A-8A	80 ns	
HB56G19A-10A	100 ns	
HB56G19B/GB-6A	60 ns	30-pin SIP Socket Type
HB56G19B/GB-7A	70 ns	
HB56G19B/GB-8A	80 ns	
HB56G19B/GB-10A	100 ns	

Note: Following the specification of the contact pads.

HB56G19B-XX :solder
HB56G19GB-XX :gold

PIN OUT



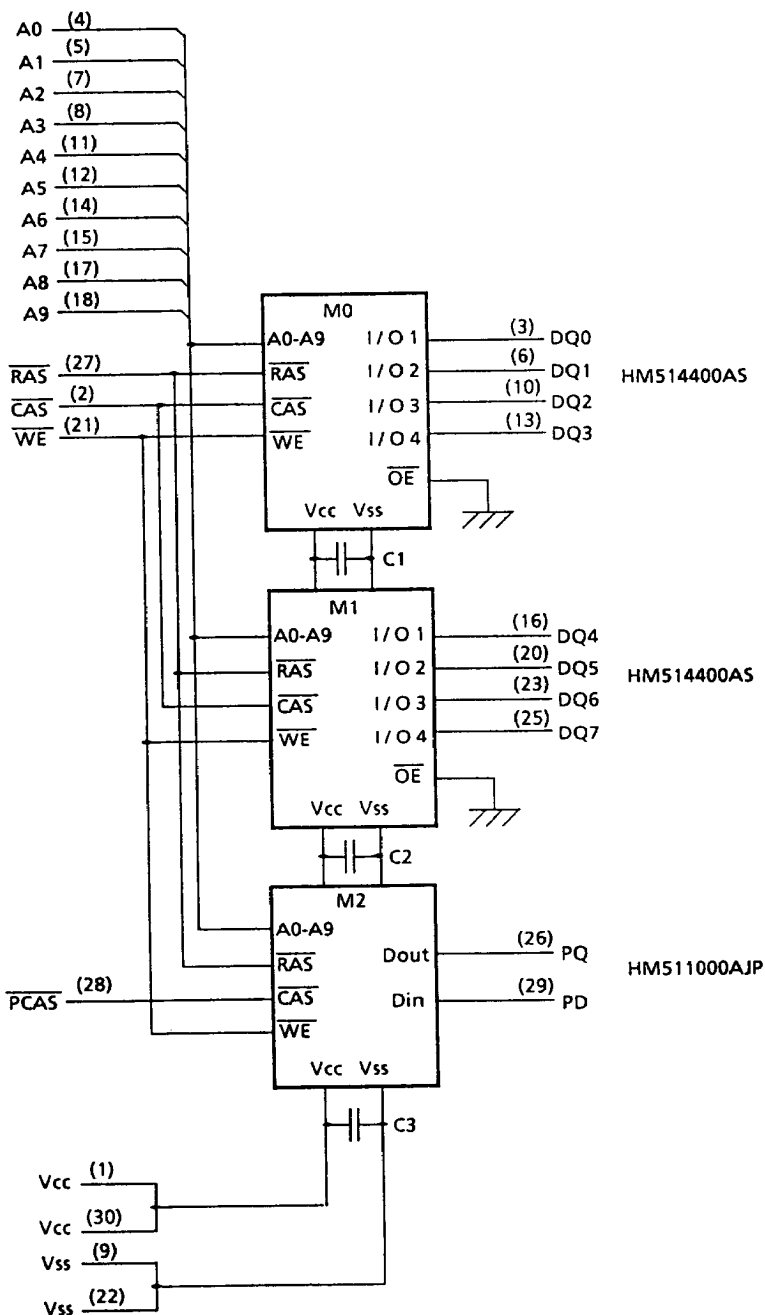
Pin No.	Pin Name	Pin No.	Pin Name
1	V _{CC}	16	DQ ₄
2	CAS	17	A ₈
3	DQ ₀	18	A ₉
4	A ₀	19	NC
5	A ₁	20	DQ ₅
6	DQ ₁	21	WE
7	A ₂	22	V _{SS}
8	A ₃	23	DQ ₆
9	V _{SS}	24	NC
10	DQ ₂	25	DQ ₇
11	A ₄	26	PQ
12	A ₅	27	RAS
13	DQ ₃	28	PCAS
14	A ₆	29	PD
15	A ₇	30	V _{CC}

PIN DESCRIPTION

Pin Name	Function
A ₀ -A ₉	Address Input
A ₀ -A ₉	Refresh Address Input
RAS	Row Address Strobe
CAS, PCAS	Column Address Strobe
WE	Read/Write Enable
DQ ₀ -DQ ₇	Data-in/Data-out
PD	Parity Data-in
PQ	Parity Data-out
V _{CC}	Power Supply (+ 5V)
V _{SS}	Ground
NC	No Connection



■ BLOCK DIAGRAM



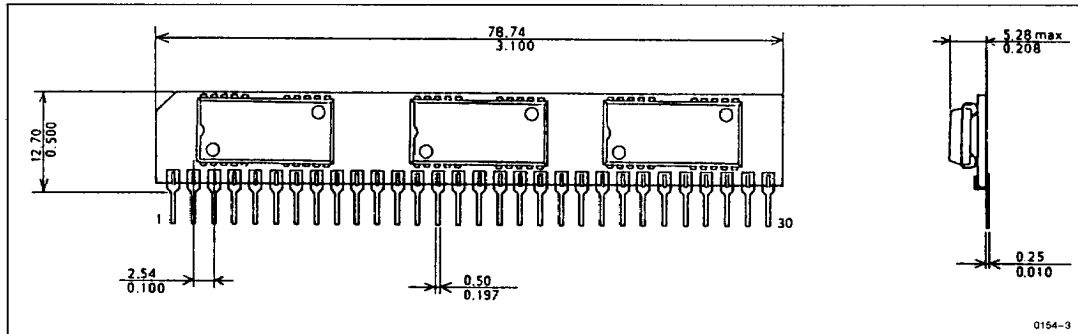
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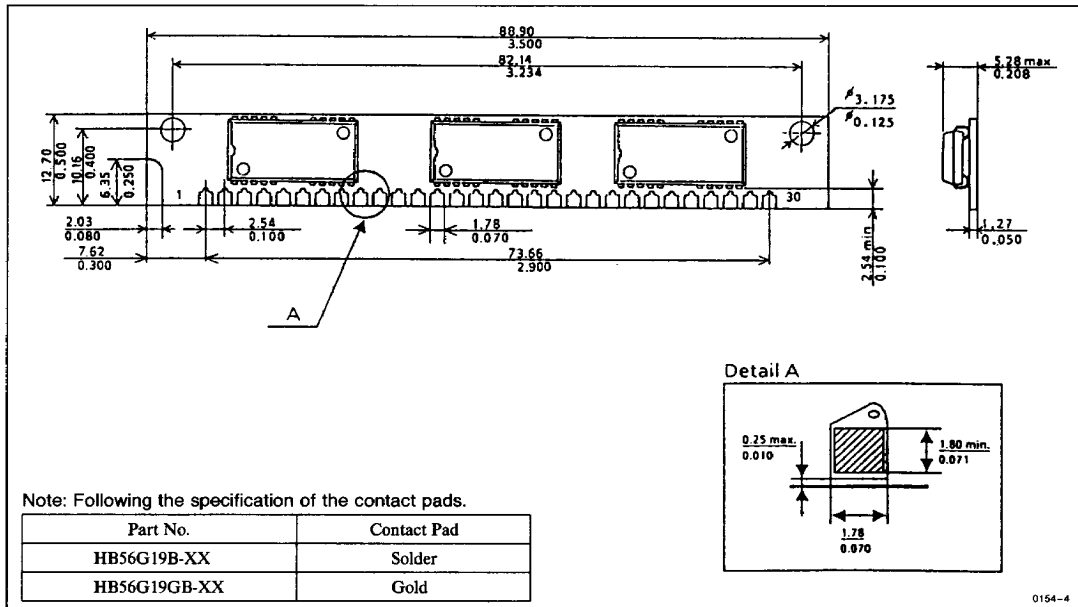
■ PHYSICAL OUTLINE

Unit: $\frac{\text{mm}}{\text{inch}}$

• HB56G19A Series



• HB56G19B/GB Series



■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Voltage on Any Pin Relative to V_{SS}	(Input) V_{in}	-1.0 to +7.0	V
	(Output) V_{out}	-1.0 to +7.0	V
Supply Voltage Relative to V_{SS}	V_{CC}	-1.0 to +7.0	V
Short Circuit Output Current	I_{out}	50	mA
Power Dissipation	P_T	8	W
Operating Temperature	T_{opr}	0 to +70	°C
Storage Temperature	T_{stg}	-55 to +125	°C

■ ELECTRICAL CHARACTERISTICS

● Recommended DC Operating Conditions ($T_A = 0$ to +70°C)

Parameter	Symbol	Min	Typ	Max	Unit	Note
Supply Voltage	V_{SS}	0	0	0	V	
	V_{CC}	4.5	5.0	5.5	V	1
Input High Voltage	V_{IH}	2.4	—	5.5	V	1
Input Low Voltage	V_{IL}	-1.0	—	0.8	V	1

Note: 1. All voltage referenced to V_{SS} .● DC Electrical Characteristics ($T_A = 0$ to +70°C, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$)

Parameter	Symbol	HB56G19A/B/GB								Unit	Test Conditions	Note
		-6A		-7A		-8A		-10A				
		Min	Max	Min	Max	Min	Max	Min	Max			
Operating Current	I _{CC1}	—	310	—	280	—	250	—	220	mA	t _{RC} = Min	1, 2
Standby Current	I _{CC2}	—	6	—	6	—	6	—	6	mA	TTL Interface RAS, CAS = V _{IH} , D _{out} = High-Z	
		—	3	—	3	—	3	—	3	mA	CMOS Interface RAS, CAS ≥ V _{CC} − 0.2V, D _{out} = High-Z	
RAS Only Refresh Current	I _{CC3}	—	310	—	280	—	240	—	210	mA	t _{RC} = Min	2
Standby Current	I _{CC5}	—	15	—	15	—	15	—	15	mA	RAS = V _{IH} , CAS = V _{IL} , D _{out} = Enable	1
CAS Before RAS Refresh Current	I _{CC6}	—	300	—	270	—	240	—	210	mA	t _{RC} = Min	
Fast Page Mode Current	I _{CC7}	—	300	—	270	—	230	—	210	mA	t _{PC} = Min	1, 3
Input Leakage Current	I _{LI}	− 10	10	− 10	10	− 10	10	− 10	10	μA	0V ≤ V _{in} ≤ 7V	
Output Leakage Current	I _{LO}	− 10	10	− 10	10	− 10	10	− 10	10	μA	0V ≤ V _{out} ≤ 7V, D _{out} = Disable	
Output High Voltage	V _{OH}	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	V	I _{out} = − 5 mA	
Output Low Voltage	V _{OL}	0	0.4	0	0.4	0	0.4	0	0.4	V	I _{out} = 4.2 mA	

- Notes: 1. I_{CC} depends on output load condition when the device is selected, I_{CC} max is specified at the output open condition.
 2. Address can be changed less than three times while $\overline{\text{RAS}} = V_{IL}$.
 3. Address can be changed ≤ 1 time while CAS = V_{IH} .



• **Capacitance** ($T_A = 25^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$)

Parameter	Symbol	Typ	Max	Unit	Note
Input Capacitance (Address)	C_{I1}	—	30	pF	1
Input Capacitance (Clock)	C_{I2}	—	36	pF	1
Input/Output Capacitance (DQ_{0-7})	$C_{I/O}$	—	17	pF	1, 2
Input Capacitance (PD)	C_{I3}	—	10	pF	1
Output Capacitance (PQ)	C_O	—	12	pF	1, 2

Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.

2. $\overline{\text{CAS}} = V_{IH}$ to disable D_{out} .

• **AC Electrical Characteristics** ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{SS} = 0\text{V}$)^{1, 2}

Read, Write, and Refresh Cycles (Common Parameters)

Parameter	Symbol	HB56G19A/B/GB								Unit	Note
		-6A		-7A		-8A		-10A			
		Min	Max	Min	Max	Min	Max	Min	Max		
Random Read or Write Cycle Time	t _{RC}	120	—	130	—	160	—	190	—	ns	
RAS Precharge Time	t _{RP}	50	—	50	—	70	—	80	—	ns	
RAS Pulse Width	t _{RAS}	60	10000	70	10000	80	10000	100	10000	ns	
CAS Pulse Width	t _{CAS}	20	10000	20	10000	25	10000	25	10000	ns	
Row Address Setup Time	t _{ASR}	0	—	0	—	0	—	0	—	ns	
Row Address Hold Time	t _{RAH}	10	—	10	—	12	—	15	—	ns	
Column Address Setup Time	t _{ASC}	0	—	0	—	0	—	0	—	ns	
Column Address Hold Time	t _{CAH}	15	—	15	—	20	—	20	—	ns	
RAS to CAS Delay Time	t _{RCD}	20	40	20	50	22	55	25	75	ns	8
RAS to Column Address Delay Time	t _{RAD}	15	30	15	35	17	40	20	55	ns	9
RAS Hold Time	t _{RSH}	20	—	20	—	25	—	25	—	ns	
CAS Hold Time	t _{CSH}	60	—	70	—	80	—	100	—	ns	
CAS to RAS Precharge Time	t _{CRP}	10	—	10	—	10	—	10	—	ns	
Transition Time (Rise and Fall)	t _T	3	50	3	50	3	50	3	50	ns	7
Refresh Period	t _{REF}	—	16	—	16	—	16	—	16	ms	15



Read Cycle

Parameter	Symbol	HB56G19A/B/GB								Unit	Note
		-6A		-7A		-8A		-10A			
		Min	Max	Min	Max	Min	Max	Min	Max		
Access Time from RAS	t _{RAC}	—	60	—	70	—	80	—	100	ns	2, 3
Access Time from CAS	t _{CAC}	—	20	—	20	—	25	—	25	ns	3, 4
Access Time from Address	t _{AA}	—	30	—	35	—	40	—	45	ns	3, 5
Read Command Setup Time	t _{RCS}	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to CAS	t _{RCH}	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to RAS	t _{RRH}	10	—	10	—	10	—	10	—	ns	
Column Address to RAS Lead Time	t _{RAL}	30	—	35	—	40	—	45	—	ns	
Output Buffer Turn-off Time	t _{OFF}	0	20	0	20	0	20	0	25	ns	6

Write Cycle

Write Cycle

Parameter	Symbol	HB56G19A/B/GB								Unit	Note
		-6A		-7A		-8A		-10A			
		Min	Max	Min	Max	Min	Max	Min	Max		
Write Command Setup Time	tWCS	0	—	0	—	0	—	0	—	ns	10
Write Command Hold Time	tWCH	15	—	15	—	20	—	20	—	ns	
Write Command Pulse Width	tWP	10	—	10	—	15	—	20	—	ns	
Data-in Setup Time	tDS	0	—	0	—	0	—	0	—	ns	11
Data-in Hold Time	tDH	15	—	15	—	20	—	20	—	ns	11



Refresh Cycle

Parameter	Symbol	HB56G19A/B/GB								Unit	Note
		-6A		-7A		-8A		-10A			
		Min	Max	Min	Max	Min	Max	Min	Max		
CAS Setup Time (CAS Before RAS Refresh Cycle)	t _{CSR}	10	—	10	—	10	—	10	—	ns	
CAS Hold Time (CAS Before RAS Refresh Cycle)	t _{CHR}	15	—	15	—	20	—	20	—	ns	
RAS Precharge to CAS Hold Time	t _{RPC}	10	—	10	—	10	—	10	—	ns	

Fast Page Mode Cycle

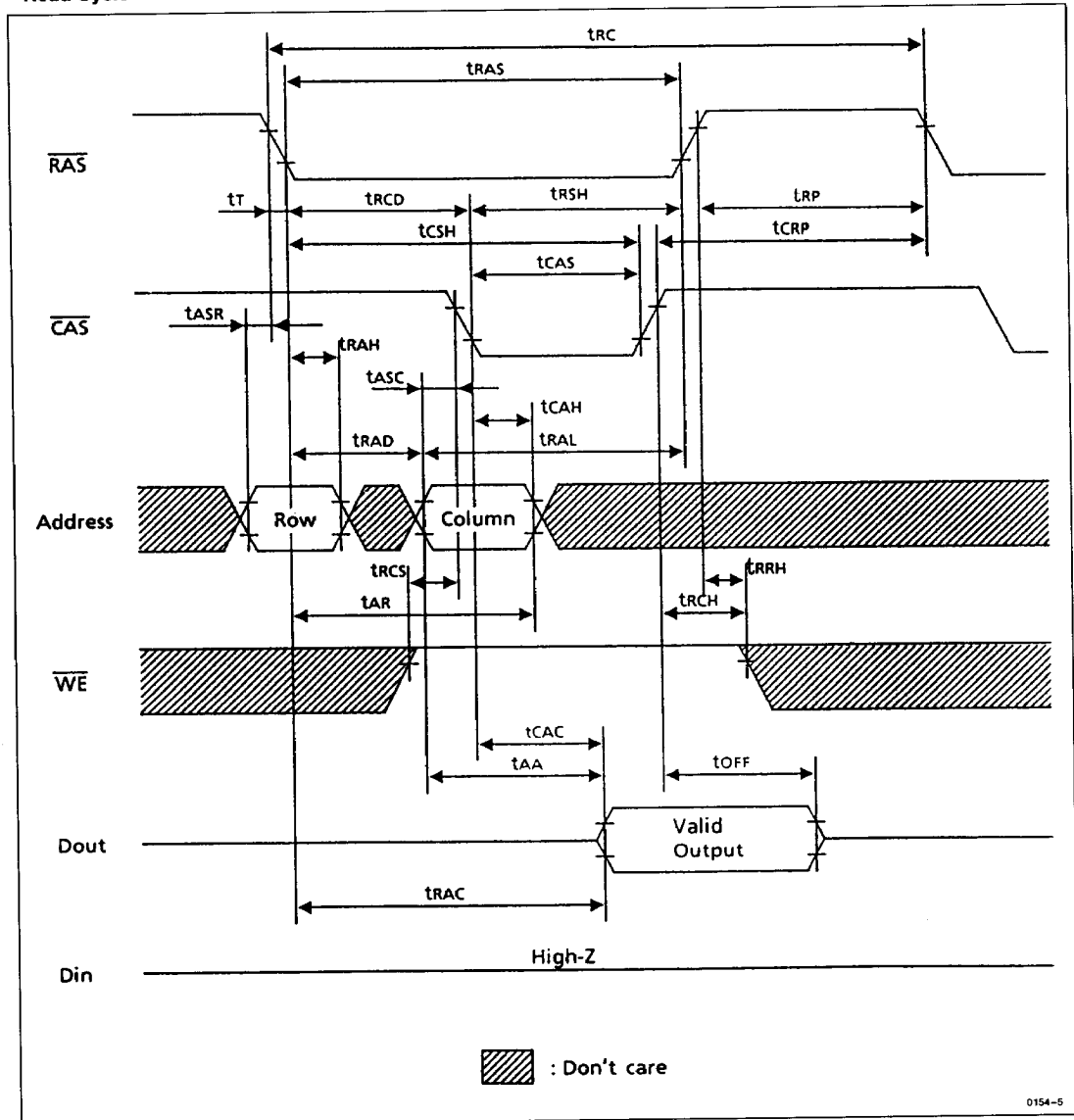
Parameter	Symbol	HB56G19A/B/GB								Unit	Note
		-6A		-7A		-8A		-10A			
		Min	Max	Min	Max	Min	Max	Min	Max		
Fast Page Mode Cycle Time	t _{PC}	45	—	50	—	55	—	55	—	ns	
Fast Page Mode CAS Precharge Time	t _{CP}	10	—	10	—	10	—	10	—	ns	
Fast Page Mode RAS Pulse Width	t _{RASC}	60	100000	70	100000	80	100000	100	100000	ns	13
Access Time from CAS Precharge	t _{ACP}	—	40	—	45	—	50	—	50	ns	14
RAS Hold Time from CAS Precharge	t _{RHCP}	40	—	45	—	50	—	50	—	ns	

- Notes:
1. AC measurements assume $t_T = 5$ ns.
 2. Assumes that $t_{RCD} \leq t_{RCD}(\text{max})$ and $t_{RAD} \leq t_{RAD}(\text{max})$. If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.
 3. Measured with a load circuit equivalent to 2 TTL loads and 100 pF.
 4. Assumes that $t_{RCD} \geq t_{RCD}(\text{max})$ and $t_{RAD} \leq t_{RAD}(\text{max})$.
 5. Assumes that $t_{RCD} \leq t_{RCD}(\text{max})$ and $t_{RAD} \geq t_{RAD}(\text{max})$.
 6. $t_{OFF}(\text{max})$ defines the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
 7. $V_{IH}(\text{min})$ and $V_{IL}(\text{max})$ are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
 8. Operation with the $t_{RCD}(\text{max})$ limit insures that $t_{RAC}(\text{max})$ can be met, $t_{RCD}(\text{max})$ is specified as a reference point only, if t_{RCD} is greater than the specified $t_{RCD}(\text{max})$ limit, then access time is controlled exclusively by t_{CAC} .
 9. Operation with the $t_{RAD}(\text{max})$ limit insures that $t_{RAC}(\text{max})$ can be met, $t_{RAD}(\text{max})$ is specified as a reference point only, if t_{RAD} is greater than the specified $t_{RAD}(\text{max})$ limit, then access time is controlled exclusively by t_{AA} .
 10. Early write cycle only ($t_{WCS} \geq t_{WCS}(\text{min})$).
 11. These parameters are referenced to $\overline{\text{CAS}}$ leading edge in an early write cycle.
 12. An initial pause of 100 μs is required after power up followed by a minimum of eight initialization cycles (any combination of cycles containing $\overline{\text{RAS}}$ clock such as $\overline{\text{RAS}}$ only refresh).
 13. t_{RASC} is determined by $\overline{\text{RAS}}$ pulse width in fast page mode cycles.
 14. Access time is determined by the longer of t_{AA} or t_{CAC} or t_{ACP} .
 15. t_{REF} is determined by 1,024 refresh cycles.

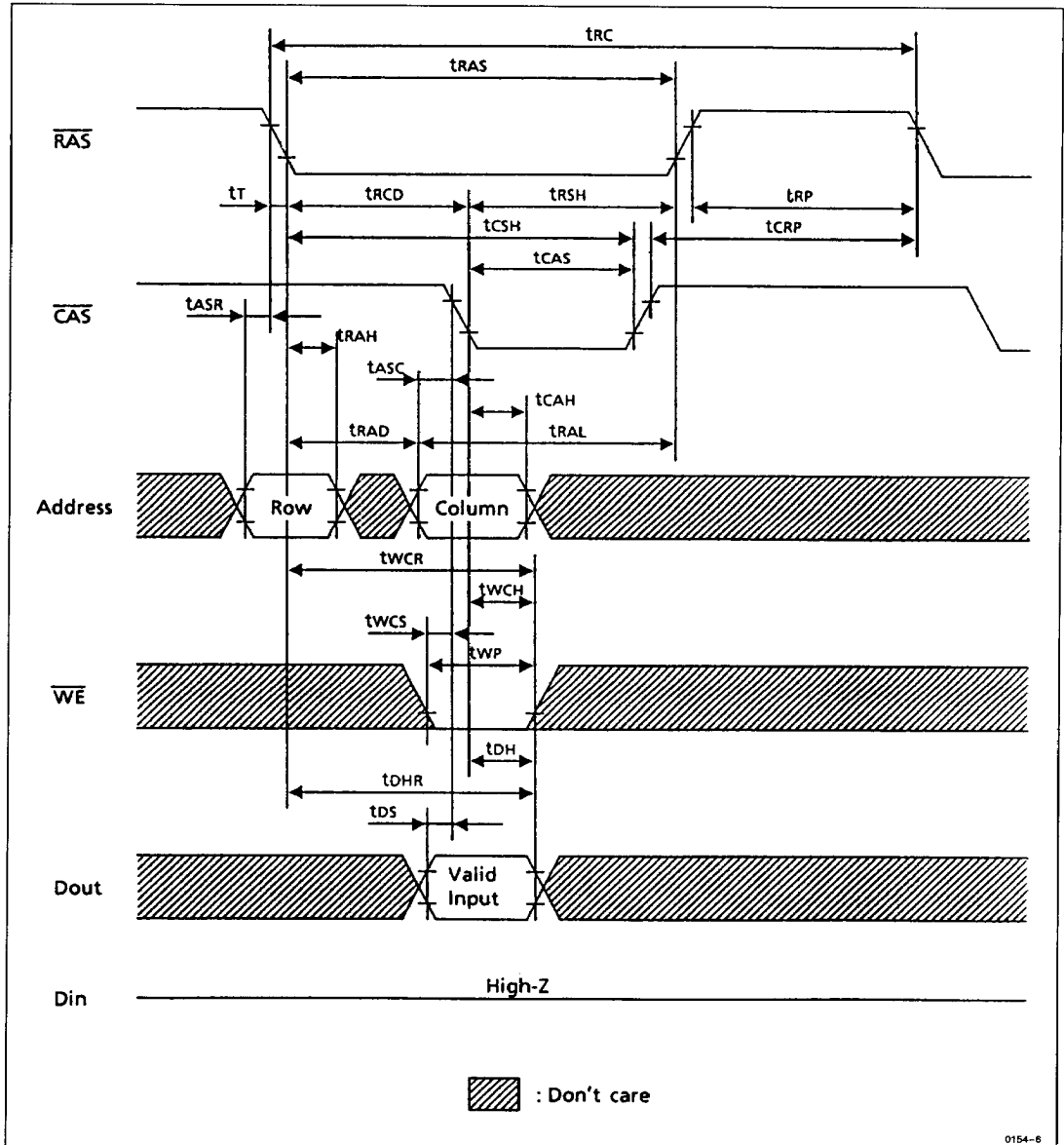


■ TIMING WAVEFORMS

• Read Cycle

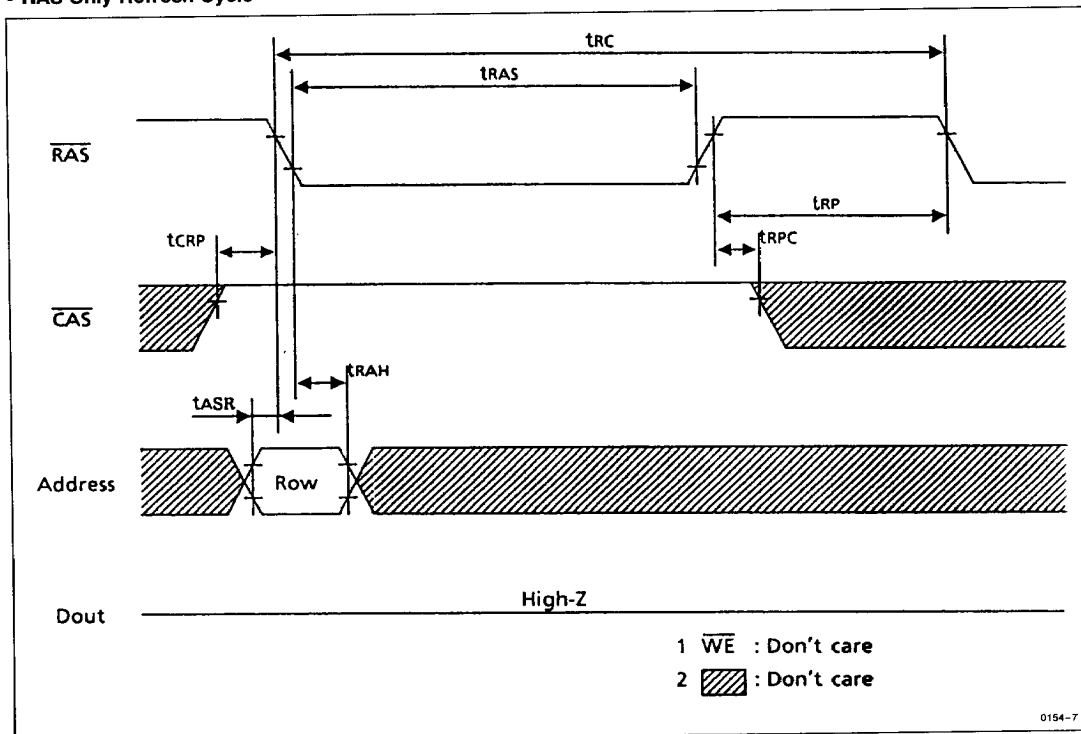
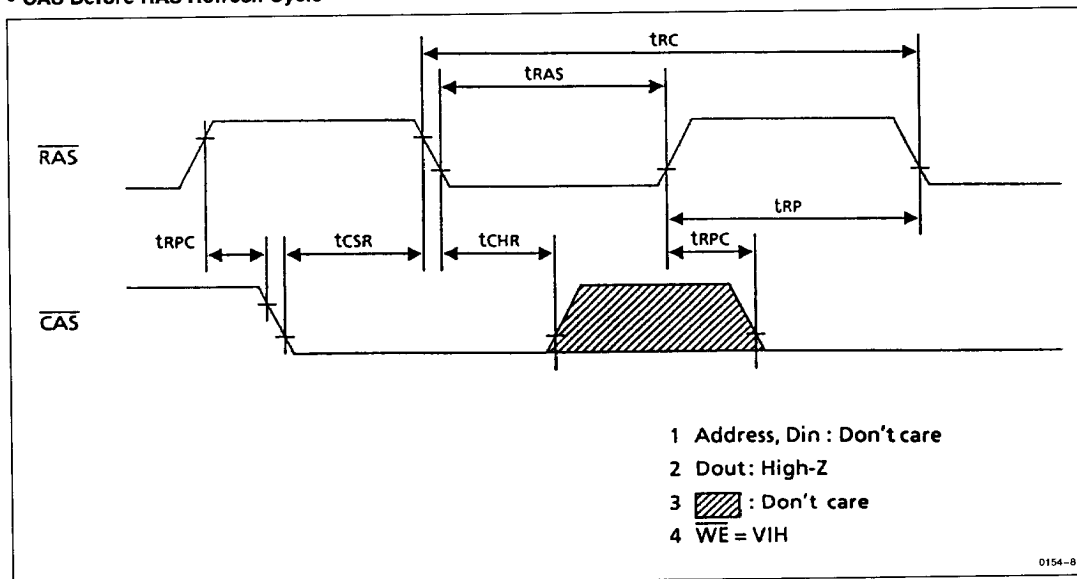


• Early Write Cycle

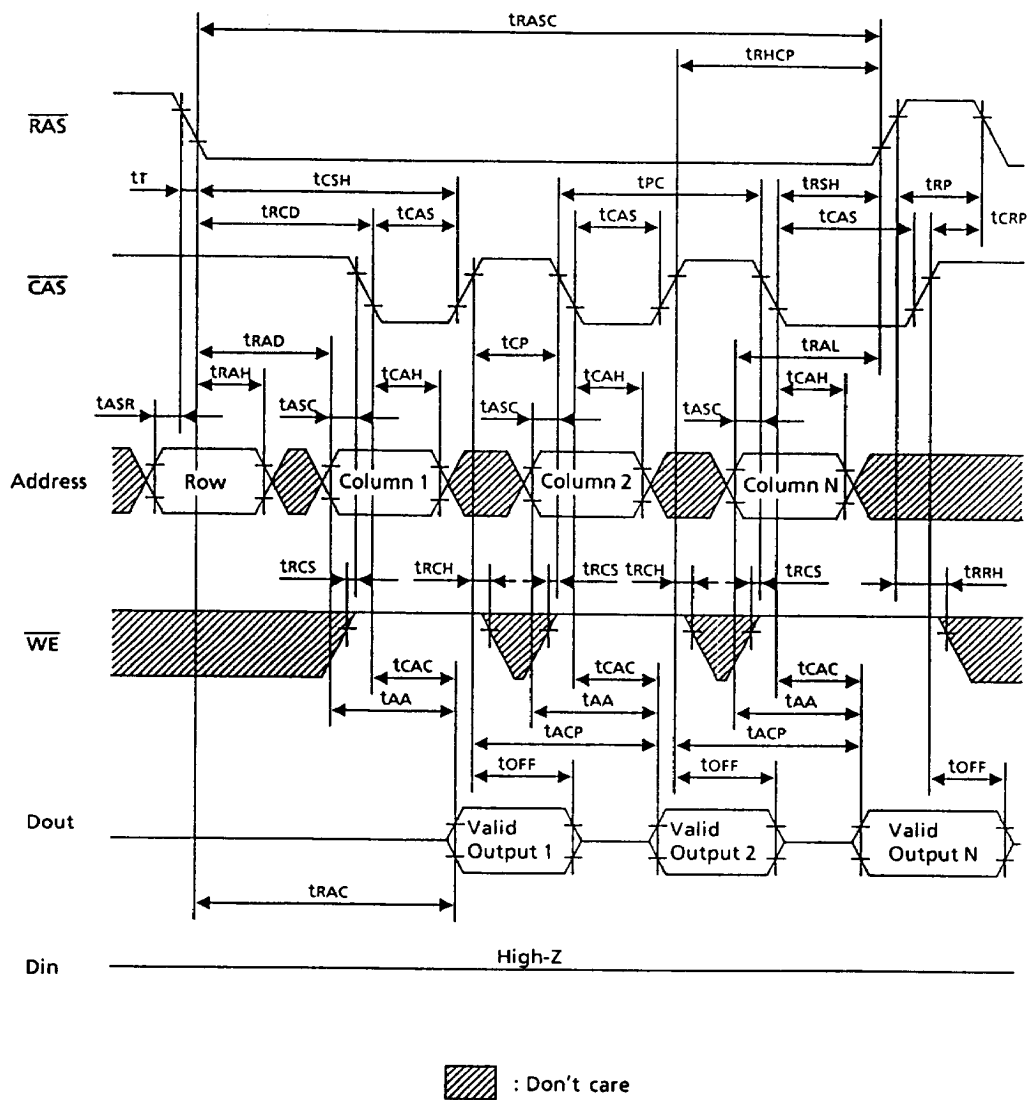


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• $\overline{\text{RAS}}$ Only Refresh Cycle• $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle

• Fast Page Mode Read Cycle



0154-9



• Fast Page Mode Early Write Cycle

